

Search Notes

Application/Control No:

10/005,224

Examiner

Hanh B. Thai

Applicant(s)/Patent under
Reexamination

BASKO ET AL.

Art Unit

2163

SEARCHED

Class	Subclass	Date	Examiner
707	1-10	4/6/2006	HT
707	203	4/6/2006	HT
709	223-224	4/6/2006	HT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
707	1, 203	4/6/2006	HT
709	223-224	4/6/2006	HT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East search (text search-updated)	4/6/2006	HT
Consulted: Kindred, Alford (primary 707)	4/4/2006	HT
IEEE search ACM search	4/6/2006	HT